

FORM PTO-1449 (MODIFIED)

ATTORNEY DOCKET NO.

SERIAL NO.

U.S. DEPT. OF PATENTS AND
PUBLICATIONS
FOR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

SP00-386

10/023,291

APPLICANT Berkey et al.

FILING DATE December 14,
2001

GROUP: 2874

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date if Approp.
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub- Class	Translation Yes No
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

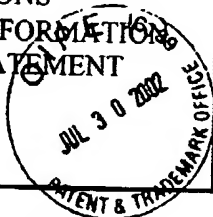
AR	Kumar et al, "Effects of Deuterium Treatments on the Optical Properties of Fused Silica", <i>Laser Induced Damage in Optical Materials: 1981</i> , pp. 268-272
AS	
AT	
AU	
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AW	

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FORM PTO-1449 (MODIFIED) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT	ATTORNEY DOCKET NO.	SERIAL NO.
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REFERENCE DESIGNATION				U.S. PATENT DOCUMENTS			
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date if Approp.
	BN	09/558,770	/	Allen et al	—	—	04/26/00
	BO	09/722,804	/	Bookbinder et al	—	—	11/27/00
	BP	09/822,168	/	Berkey et al	—	—	03/31/01
	BQ	09/996,632	/	Berkey et al	—	—	11/28/01
	BR	10/023,291	/	Berkey et al	—	—	12/14/01
	BS	60/309,160	/	Berkey et al	—	—	07/31/02

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub-Class	Translation Yes No
	BT	10-68834	03/10/98	Japan	G02B	6/16	X
	BU	55-23081	02/19/80	Japan	C03B	37/00	X
	BV	57-17433	01/29/82	Japan	C03B	37/00	X
	BW	57-34034	02/24/82	Japan	C03B	37/00	X
	BX	60-71536	04/23/85	Japan	C03B	37/018	X
	BY	60-86043	05/15/85	Japan	C03B	37/018	X
	BZ	63-225546	09/20/88	Japan	C03B	37/018	X
	CA	WO00/64824	11/02/00	PCT	C03B	37/00	
	CB	WO00/64825	11/02/00	PCT	C03B	37/014	

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	CC	Dianov et al, "Low-Hydrogen Silicon Oxynitride Optical Fibers Prepared by SPCVD", Journal of Lightwave Technology, July 1995, vol. 13, No. 7, pp. 1471-1474
	CD	Diaz de la Iglesia et al, "Loss Spread in Single-Mode Fibers Due to OH-Ion Concentration and Transmitter-Wavelength Fluctuations", International Wire & Cable Symposium Proceedings 1987, pp. 629-639
	CE	Hanawa et al, "Fabrication of Completely OH-Free V.A.D. Fibre", Electronics Letters, August 28, 1980, vol. 16, No. 18, pp. 699-700

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DATE CONSIDERED: 6-03

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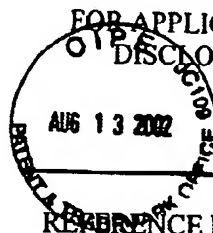
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